



**ALPHA & OMEGA**  
SEMICONDUCTOR

**AOH3254**

**150V N-Channel MOSFET**

### General Description

- Trench Power MV MOSFET technology
- Low  $R_{DS(ON)}$
- Low Gate Charge
- Optimized for fast-switching applications

### Product Summary

$V_{DS}$	150V
$I_D$ (at $V_{GS}=10V$ )	5A
$R_{DS(ON)}$ (at $V_{GS}=10V$ )	< 63mΩ
$R_{DS(ON)}$ (at $V_{GS}=4.5V$ )	< 77mΩ

### Applications

- Synchronous Rectification in DC/DC and AC/DC Converters
- Industrial and Motor Drive applications

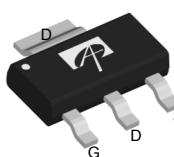
100% UIS Tested

100%  $R_g$  Tested

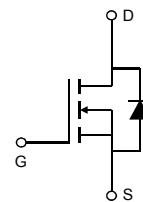
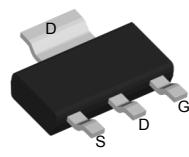


SOT223

Top View



Bottom View



Orderable Part Number	Package Type	Form	Minimum Order Quantity
AOH3254	SOT223	Tape & Reel	2500

### Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	150	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current <sup>A</sup>	$I_D$	5	A
$T_A=70^\circ C$		4	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	20	
Avalanche Current <sup>C</sup>	$I_{AS}$	15	A
Avalanche energy $L=0.3mH$ <sup>C</sup>	$E_{AS}$	34	mJ
$V_{DS}$ Spike	$10\mu s$	$V_{SPIKE}$	V
	$T_A=25^\circ C$	180	
	$T_A=70^\circ C$	4.1	
Power Dissipation <sup>B</sup>	$P_D$	2.6	W
$T_A=70^\circ C$		-55 to 150	
Junction and Storage Temperature Range	$T_J, T_{STG}$		°C

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	25	30	°C/W
Maximum Junction-to-Ambient <sup>A,D</sup> Steady-State		50	60	°C/W
Maximum Junction-to-Lead	$R_{\theta JL}$	10	15	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	150			V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=150\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$		1	5	$\mu\text{A}$
$I_{GSS}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm20\text{V}$			$\pm100$	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1.7	2.15	2.7	V
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=5\text{A}$ $T_J=125^\circ\text{C}$		52	63	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=2\text{A}$		102	123	
$g_{FS}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=5\text{A}$		60	77	$\text{m}\Omega$
$V_{SD}$	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.72	1	V
$I_S$	Maximum Body-Diode Continuous Current				5	A
<b>DYNAMIC PARAMETERS</b>						
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=75\text{V}, f=1\text{MHz}$		675		pF
$C_{oss}$	Output Capacitance			78		pF
$C_{rss}$	Reverse Transfer Capacitance			4		pF
$R_g$	Gate resistance	$f=1\text{MHz}$	1.4	2.9	4.4	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=75\text{V}, I_D=5\text{A}$		11.5	20	nC
$Q_g(4.5\text{V})$	Total Gate Charge			5.5	10	nC
$Q_{gs}$	Gate Source Charge			2		nC
$Q_{gd}$	Gate Drain Charge			2.5		nC
$t_{D(\text{on})}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=75\text{V}, R_L=15\Omega, R_{\text{GEN}}=3\Omega$		6		ns
$t_r$	Turn-On Rise Time			3		ns
$t_{D(\text{off})}$	Turn-Off Delay Time			20		ns
$t_f$	Turn-Off Fall Time			5		ns
$t_{rr}$	Body Diode Reverse Recovery Time	$I_F=5\text{A}, dI/dt=500\text{A}/\mu\text{s}$		37		ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	$I_F=5\text{A}, dI/dt=500\text{A}/\mu\text{s}$		210		nC

A. The value of  $R_{QJA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^\circ\text{C}$ . The value in any given application depends on the user's specific board design.

B. The power dissipation  $P_D$  is based on  $T_{J(\text{MAX})}=150^\circ\text{C}$ , using  $\leq 10\text{s}$  junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature  $T_{J(\text{MAX})}=150^\circ\text{C}$ . Ratings are based on low frequency and duty cycles to keep initial  $T_J=25^\circ\text{C}$ .

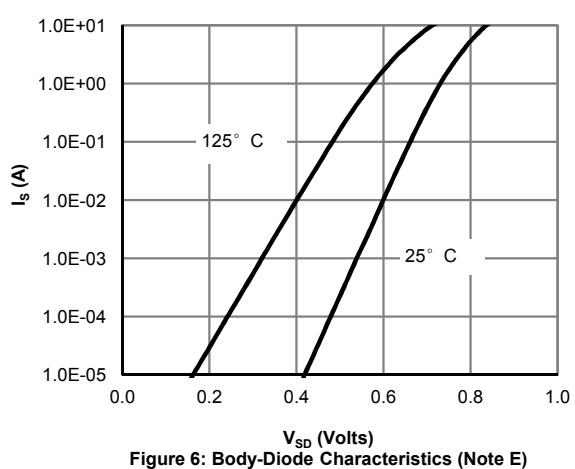
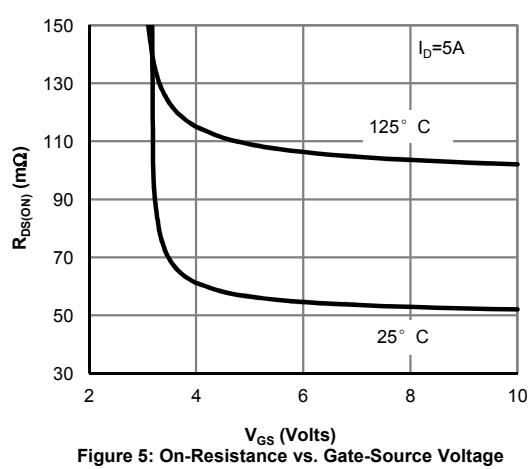
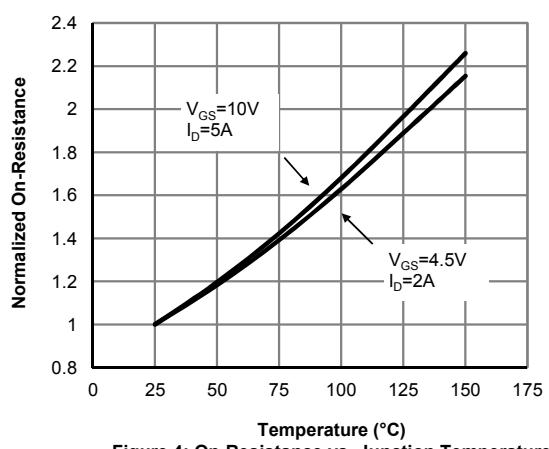
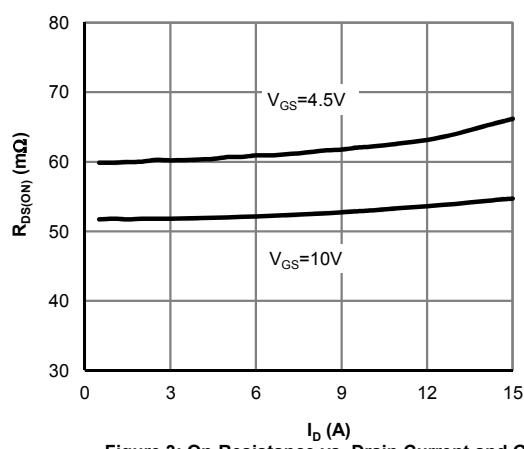
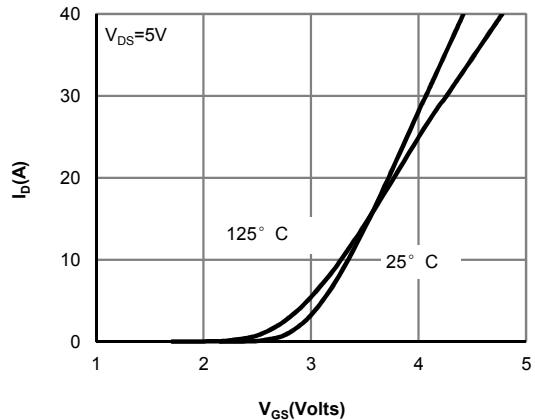
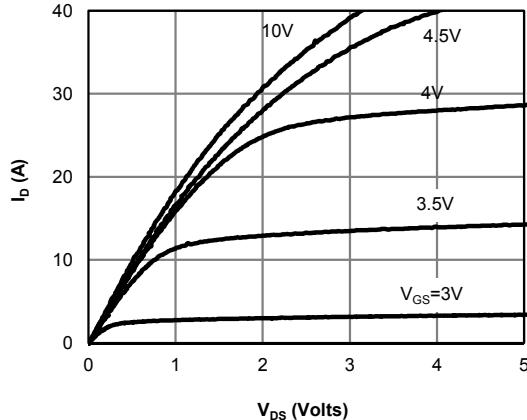
D. The  $R_{QJA}$  is the sum of the thermal impedance from junction to lead  $R_{QJL}$  and lead to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, assuming a maximum junction temperature of  $T_{J(\text{MAX})}=150^\circ\text{C}$ . The SOA curve provides a single pulse rating.

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## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



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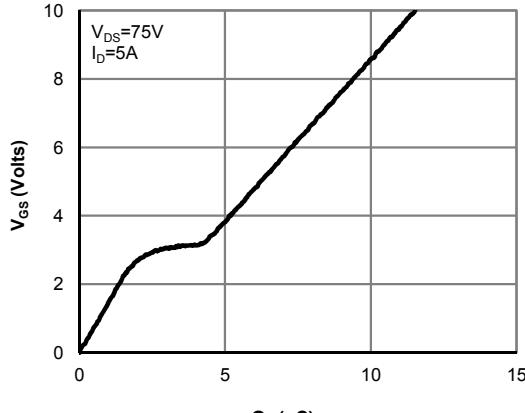


Figure 7: Gate-Charge Characteristics

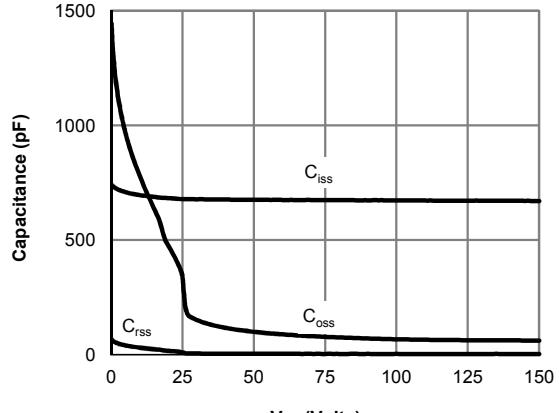


Figure 8: Capacitance Characteristics

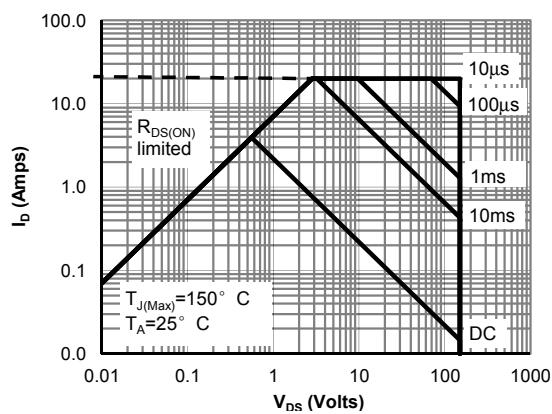


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

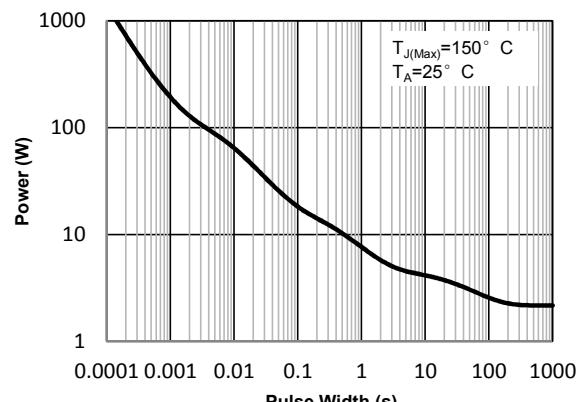


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

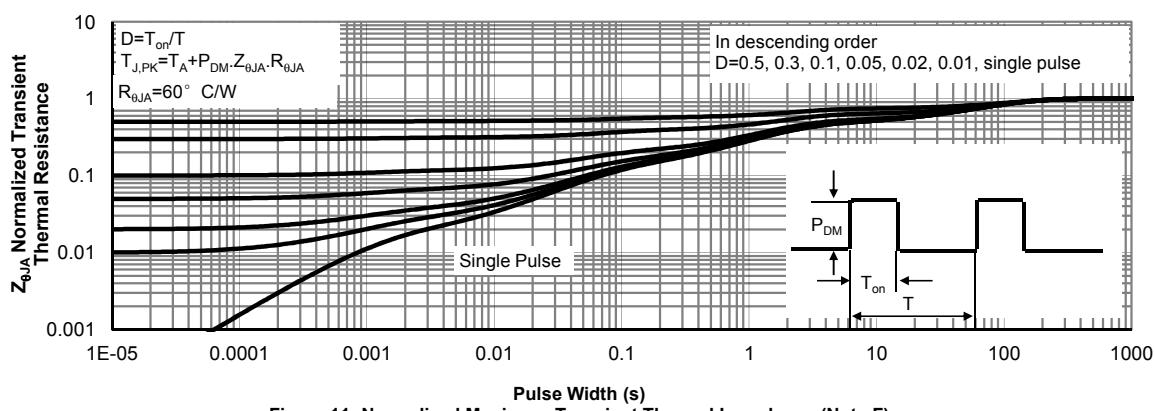
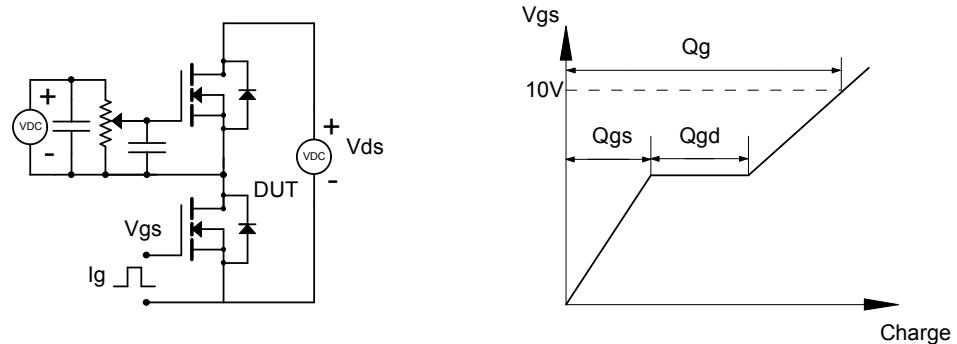
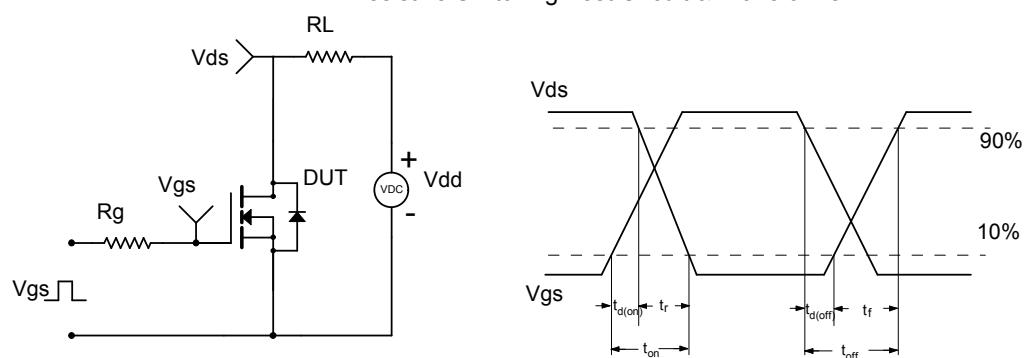


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

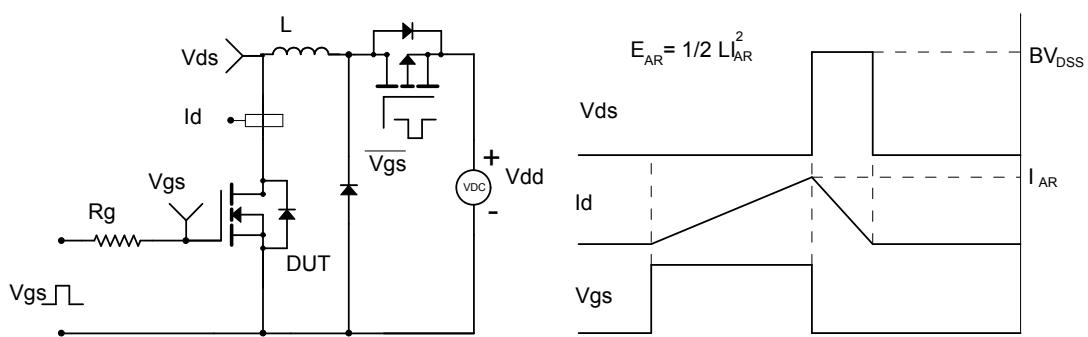
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

